

**Notice of References Cited**

Application/Control No.

10/022,150

Applicant(s)/Patent Under  
Reexamination  
FEWSTER ET AL.

Examiner

Allen C. Ho

Art Unit

2882

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,226,349 B1	05-2001	Schuster et al.	378/84
	B	US-5,878,106	03-1999	Fujiwara	378/79
	C	US-			
	D	US-			
	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	B. D. Cullity. Elements of X-Ray Diffraction, second edition (Reading, MA: Addison-Wesley, 1978), p. 156-158.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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